Abstract of the Disclosure:

A method of determining the critical path of a circuit includes first determining the paths, their mean path transit times and their path transit time fluctuations. Paths having

5   similar statistical parameters are combined to form one path group. For each path group, a statistical group figure is, then, calculated and, for the totality of paths considered, a statistical total figure is calculated. Finally, the critical paths of the circuit are determined by taking into

10   consideration the total figure, comparing the group figures at or above a critical path transit time Tc.

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